

TESCAN

TESCAN's SEM, FIB-SEM, and micro-CT instruments are capable of providing valuable insights into a broad range of scientific disciplines. From materials science to cellular biology, semiconductors, and geology, our instruments help unlock the secrets of "How" and "Why."

TESCAN has developed state-of-the-art SEMs, FIB-SEMs, and micro-CTs that are capable of imaging with both high resolution and high contrast - some solutions will even enable observation of dynamic events in real-time. Furthermore, these systems have been designed to be extremely versatile, allowing customization of a system by adding imaging and microanalytical detection capabilities. This culmination of performance and versatility, produce intricate experimental capabilities that result in the most comprehensive analyses.

SEM, FIB-SEM and micro-CT solutions:

- **TESCAN MAGNA** – Triglav™ UHRSEM with TriLens™ immersion optics for characterization of nanomaterials
- **TESCAN SOLARIS** – Triglav™ An ultimate resolution FIB-SEM workbench for advanced nanofabrication applications
- **TESCAN SOLARIS X** – Triglav™ A Plasma FIB-SEM platform for deep sectioning and the highest resolution end-pointing for package level failure analysis
- **TESCAN CLARA** – BrightBeam™ Field-free analytical UHR-SEM for materials characterization at the nanoscale
- **TESCAN AMBER** – BrightBeam™ A field-free UHR-SEM combined with the most precise FIB for sample preparation, sub-surface and 3D analysis capabilities to take your materials nanocharacterization further
- **TESCAN AMBER X** – BrightBeam™ A unique combination of Plasma FIB and field-free UHR SEM for the widest range of multiscale materials characterization applications
- **TESCAN TIMA** – High speed measurement and analysis of large batches of mineralogy samples
- **TESCAN CoreTOM** – Multi-resolution 3D X-ray microscope optimized for high resolution, large field of view imaging of full cores down to microplugs
- **TESCAN DynaTOM** – Unique and first of its kind dedicated system for fast dynamic in situ imaging
- **TESCAN UniTOM XL** – Enables high-throughput non-destructive 3D imaging for materials research, failure analysis and quality assurance
- **TESCAN VEGA** – Analytical SEM for routine materials characterization, research and quality control applications at the micron scale
- **TESCAN MIRA** – Field-emission SEM with a flexible platform. It is a high-resolution analytical SEM for routine materials characterization, research and quality control applications at the sub-micron scale

The company is focused on research, development and the manufacturing of equipment for the following:

- Scanning electron microscopes and ion beam stations
- Ion beam technology
- X-ray micro-CT systems
- Special vacuum chambers and custom systems
- Supplementary accessories for SEM's
- Scientific software compatible with Windows upgrades



How to find us

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